

**ABSTRACT**

The present disclosure relates to a method for testing a circuit having analog components. The method comprises performing a low-cost optimized test on the circuit by applying an optimized input stimulus to the circuit, capturing the circuit response to the input stimulus applied to the circuit, evaluating the circuit response to predict whether the performance parameters of the circuit satisfies predetermined specifications for the circuit, and making a pass/fail determination for the circuit based upon the evaluation of the circuit response.